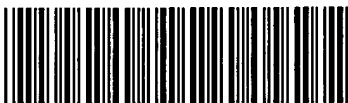


Search Notes

Application N .

10/670,520

Examiner

Stephen W. Smoot

Applicant(s)

ASAKAWA ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
257	775	6/24/2004	SWS
257	E23.169	6/24/2004	SWS
257	E23.174	6/24/2004	SWS
174	262	6/24/2004	SWS
200	264	6/24/2004	SWS
428	550	6/24/2004	SWS
428	566	6/24/2004	SWS
430	5	6/24/2004	SWS
430	269	6/24/2004	SWS

S.W.S.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Considered all references cited in parent application.	6/24/2004	S.W.S., SWS
Key Words: Porous Material - Pores, Voids, Substrate; Mask, Photomask;	6/24/2004	S.W.S., SWS
Conductor, Metal - Infiltrate, Impregnate, Via, Feedthrough, Trace, Throughhole, Interconnect, Wiring.	6/24/2004	S.W.S., SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	6/24/2004	S.W.S., SWS